



Features

- Proprietary α SiC MOSFET technology
- Low loss, fast switching speeds with low R_G
- Optimized drive voltage ($V_{GS} = 15V$) for broad driver compatibility
- Robust body diode and low Q_{rr}
- AEC-Q101 Automotive Qualified

Product Summary

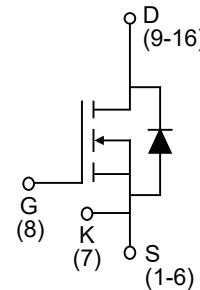
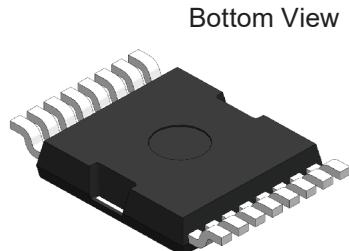
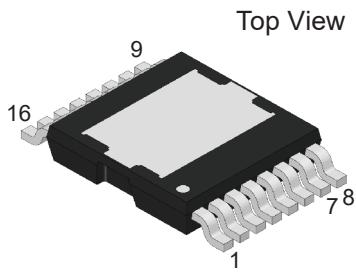
V_{DS} @ T_J, max	1200 V
I_{DM}	200A
$R_{DS(ON)}$, typ	20 m Ω
Q_{rr}	290 nC
E_{oss} @ 800 V	88 μ J
100% UIS Tested	

Applications

- xEV Charger
- Electric Vehicle Supply Equipment (EVSE)
- Motor Drives
- Automotive Inverters



Pin Configuration



Ordering Part Number	Package Type	Form	Shipping Quantity
AOGT020V120X2Q	GTPAK™	Tape & Reel	800/Reel

Absolute Maximum Ratings

($T_A = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter		AOGT020V120X2Q	Units
V_{DS}	Drain-Source Voltage		1200	V
$V_{GS, MAX}$	Gate-Source Voltage	Maximum	-8/+18	V
$V_{GS,OP,TRANS}$		Max Transient ^(A)	-8/+20	
$V_{GS,OP}$		Recommended Operating ^(B)	-5/+15	
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	91	A
		$T_C=100^\circ\text{C}$	64	
I_{DM}	Pulsed Drain Current ^(C)		200	
I_{SD}	Continuous Body Diode Forward Current $V_{GS} = -5\text{V}$		81	
E_{AS}	Single Pulsed Avalanche Energy ^(D)		1.2	J
P_D	Power Dissipation ^(C)	$T_C=25^\circ\text{C}$	394	W
T_J, T_{STG}	Junction and Storage Temperature Range		-55 to 175	°C
T_L	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds ^(J)		260	°C

Electrical Characteristics

($T_A = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC						
B _{VDSS}	Drain-Source Breakdown Voltage	I _D =250 μA, V _{GS} =0V, T _J =25°C	1200			V
		I _D =250 μA, V _{GS} =0V, T _J =175°C	1200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =1200V, V _{GS} =0V			100	μA
I _{GSS}	Gate-Body Leakage Current	V _{DS} =0V, V _{GS} =+15/-5V			±200	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =27 mA	1.8	2.8	3.5	V
R _{D(on)}	Static Drain-Source On-Resistance	V _{GS} =15V, I _D =27A	T _J =25°C	20	28	mΩ
			T _J =175°C	32		mΩ
g _F	Forward Transconductance	V _{DS} =20V, I _D =27A		23		S
V _{SD}	Diode Forward Voltage	I _S =27A, V _{GS} =-5V		4.3	5	V
DYNAMIC						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =800V, f=1 MHz		5180		pF
C _{oss}	Output Capacitance			208		pF
C _{rss}	Reverse Transfer Capacitance			18		pF
E _{oss}	Coss Stored Energy			88		μJ
R _G	Gate Resistance	f=1 MHz	0.3	1	1.3	Ω
SWITCHING						
Q _g	Total Gate Charge	V _{GS} =-5/+15V, V _{DS} =800V, I _D =30A		157		nC
Q _{gs}	Gate Source Charge			57		nC
Q _{gd}	Gate Drain Charge			44		nC
t _{D(on)}	Turn-On Delay Time	V _{GS} =-5V/+15V, V _{DS} =800V, I _D =30A, R _G =2Ω L _a =60 μH		16		ns
t _r	Turn-On Rise Time			12		ns
t _{D(off)}	Turn-Off Delay Time			22		ns
t _f	Turn-Off Fall Time			11		ns
E _{on}	Turn-On Energy			349		μJ
E _{off}	Turn-Off Energy			67		μJ
E _{tot}	Total Switching Energy	FWD: AOGT020V120X2Q		416		μJ
t _{rr}	Body Diode Reverse Recovery Time			72		ns
I _{rm}	Peak Reverse Recovery Current			11		A
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =30A, dI/dt=1500A/μs, V _{GS} =-5V, V _{DS} =800V		290		nC

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
R _{θJA}	Thermal Resistance Junction-to-Ambient ^(E,F)		47	°C/W
R _{θJC}	Thermal Resistance Junction-to-Case, Top ^(G)	0.32	0.38	°C/W
Ψ _{JL}	Thermal Characterization Parameter, Junction-to-Lead (Pin 1-7)		20	°C/W
Ψ _{JL}	Thermal Characterization Parameter, Junction-to-Lead (Pin 9-16)		8	°C/W

Notes:

- A. t_{ON}<1% *(Duty Cycle)/(Frequency), t<25 hrs over lifetime
 B. Device can be operated at V_{GS}=0/15V. Actual operating V_{GS} will depend on application specifics such as parasitic inductance and dV/dt but should not exceed maximum ratings.
 C. The power dissipation P_D is based on T_{J(MAX)}=175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
 D. L=5mH, I_{AS}=22A, R_G=10Ω, Starting T_J=25°C.
 E. The value of R_{θJA} is measured with the device in a still air environment with T_A=25°C.

- F. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.
 G. The value of R_{θJC} is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175°C.
 H. The static characteristics in Figures 1 to 8 are obtained using <300µs pulses, duty cycle 0.5% max.
 I. These curves are based on R_{θJC} which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175°C. The SOA curve provides a single pulse rating.
 J. GTPAK is not recommended for wave soldering.

Typical Electrical and Thermal Characteristics

$T_A = 25^\circ\text{C}$, unless otherwise specified.

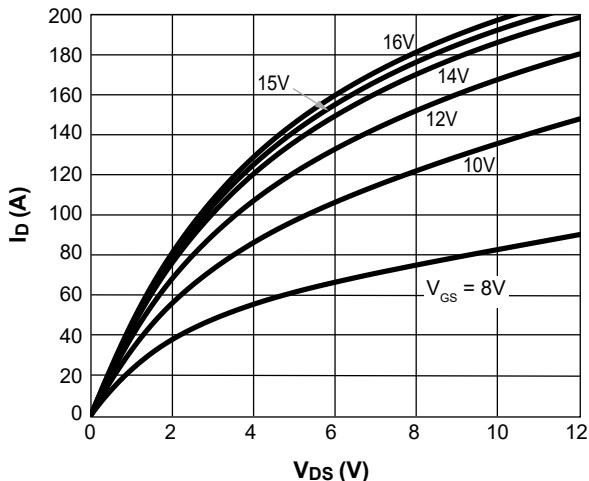


Figure 1. On-Region Characteristics $T_J = 25^\circ\text{C}$

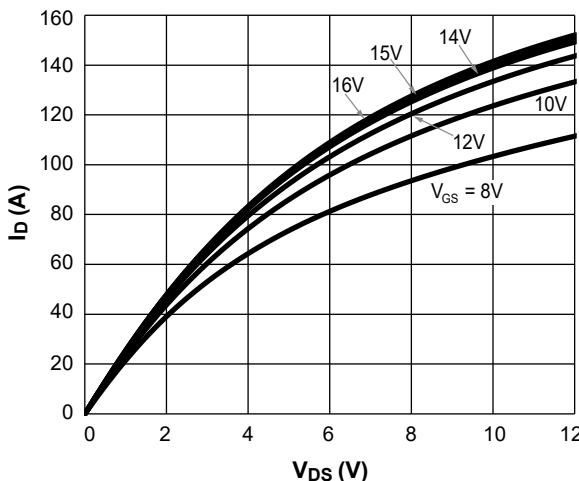


Figure 2. On-Region Characteristics $T_J = 175^\circ\text{C}$

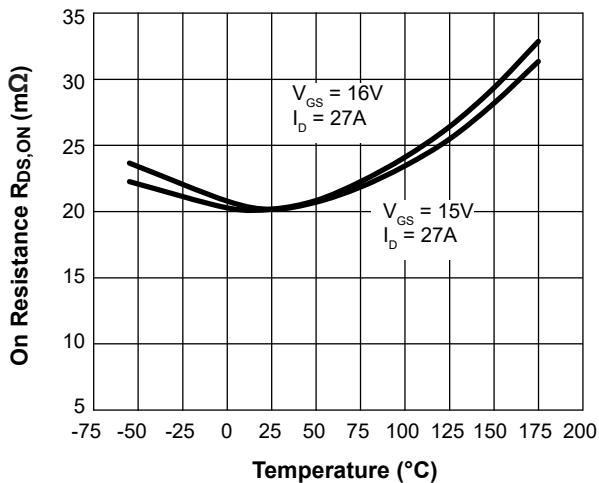


Figure 3. On Resistance vs. Junction Temperature

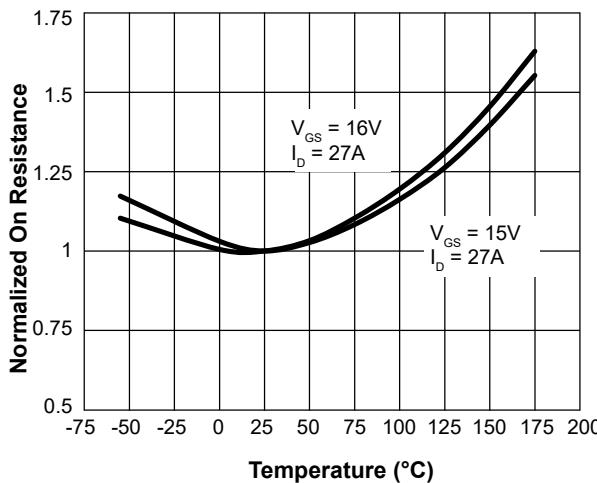


Figure 4. Normalized On Resistance vs. Junction Temperature

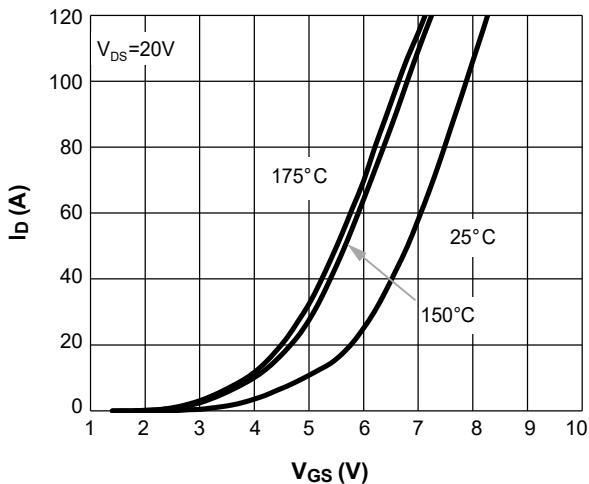


Figure 5. Transfer Characteristics

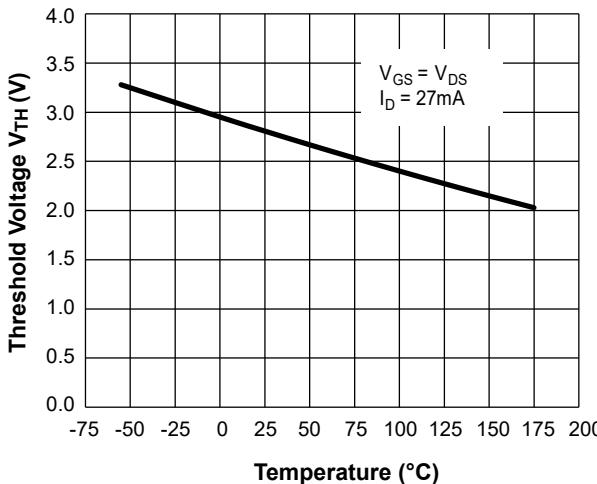


Figure 6. Threshold Voltage vs. Junction Temperature

Typical Electrical and Thermal Characteristics (Continued)

$T_A = 25^\circ\text{C}$, unless otherwise specified.

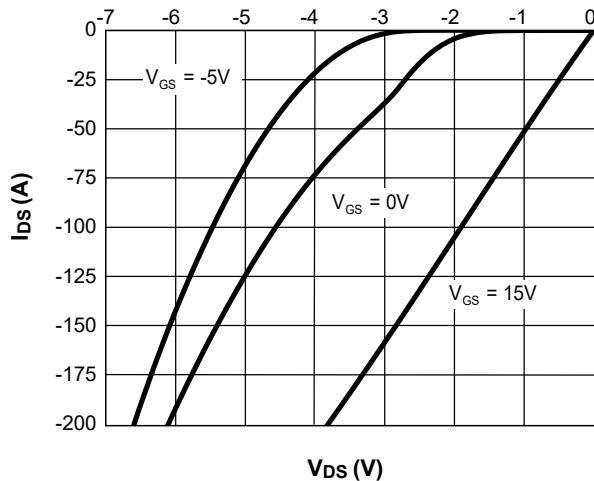


Figure 7. Body-diode Characteristics at 25°C

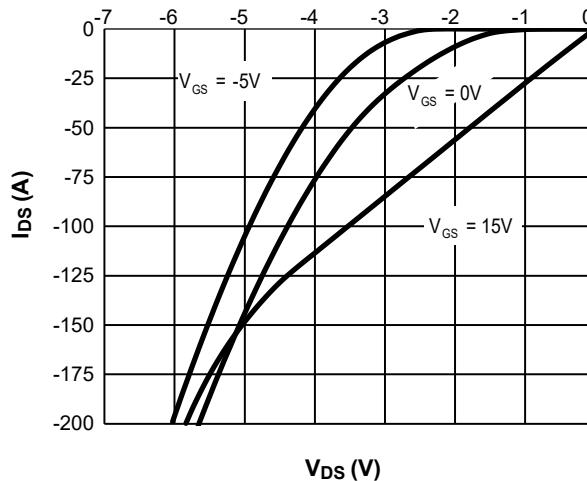


Figure 8. Body-diode Characteristics at 175°C

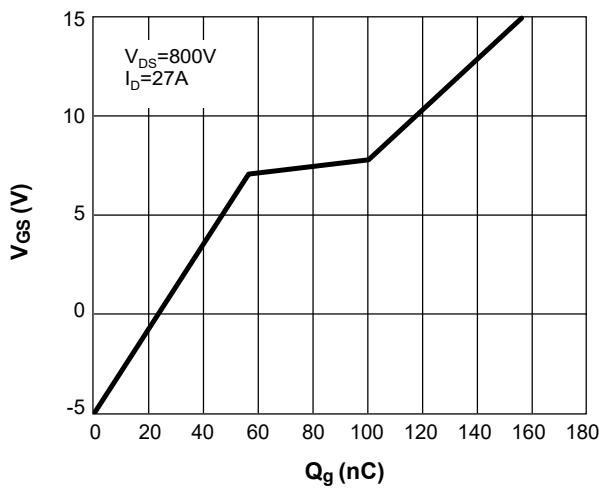


Figure 9. Gate-charge Characteristics

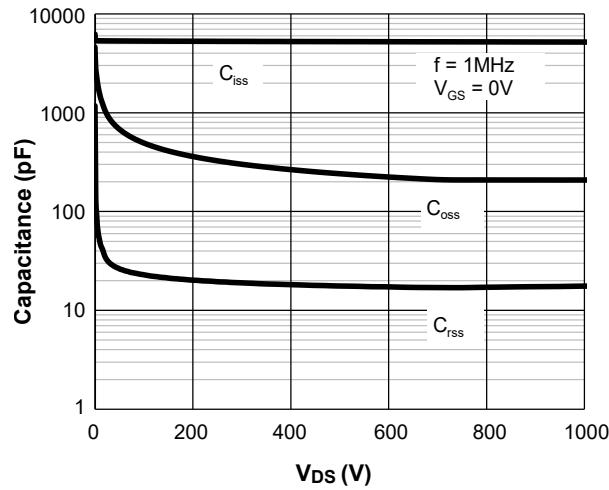


Figure 10. Capacitance Characteristics

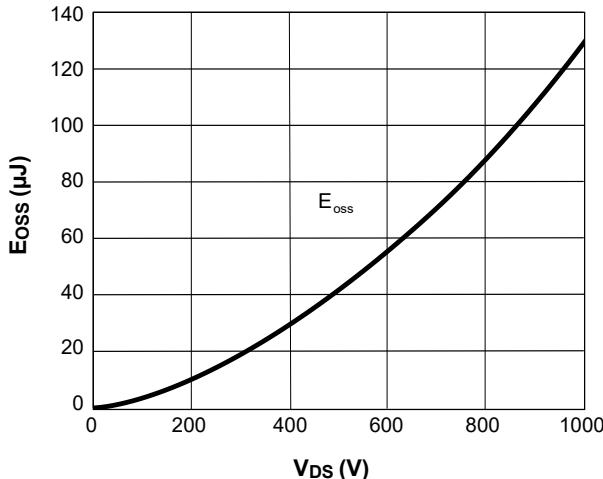


Figure 11. Coss Stored Energy

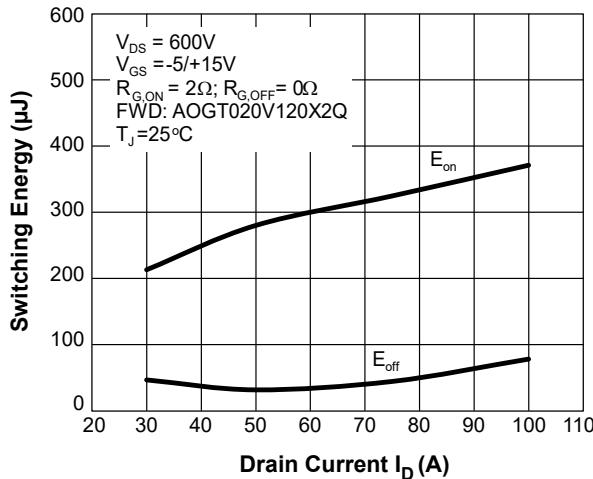


Figure 12. Switching Energy vs. Drain Current

Typical Electrical and Thermal Characteristics (Continued)

$T_A = 25^\circ\text{C}$, unless otherwise specified.

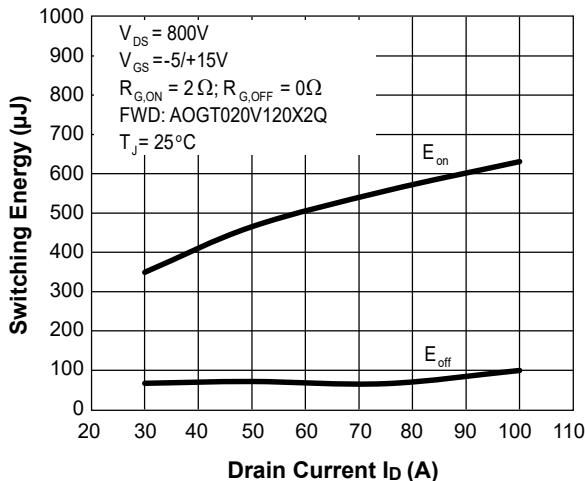


Figure 13. Switching Energy vs. Drain Current

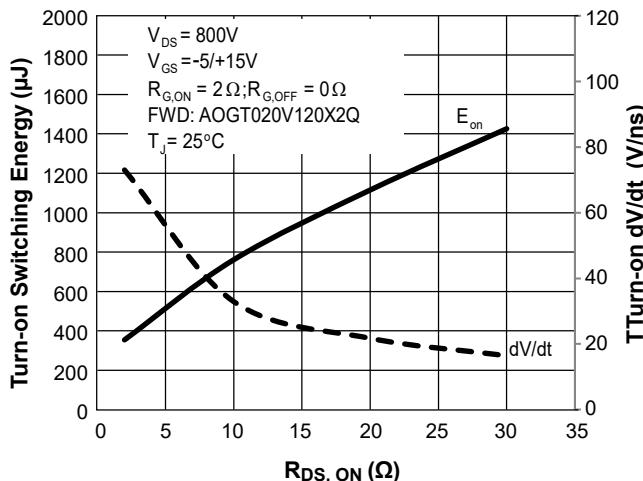


Figure 14. Turn-on Energy and dV/dt vs. External Gate Resistance

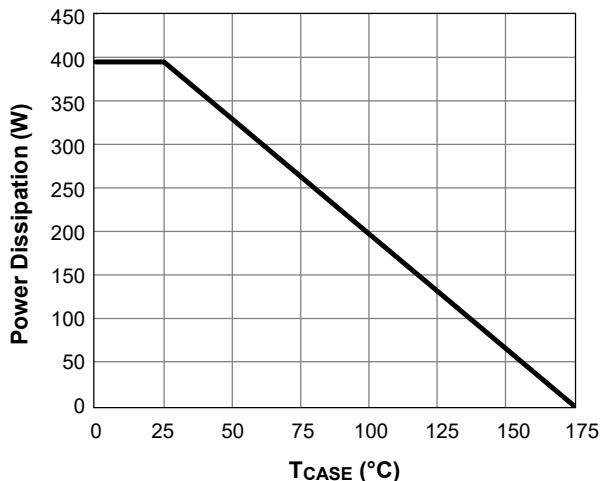


Figure 15. Power De-rating (Note 1)

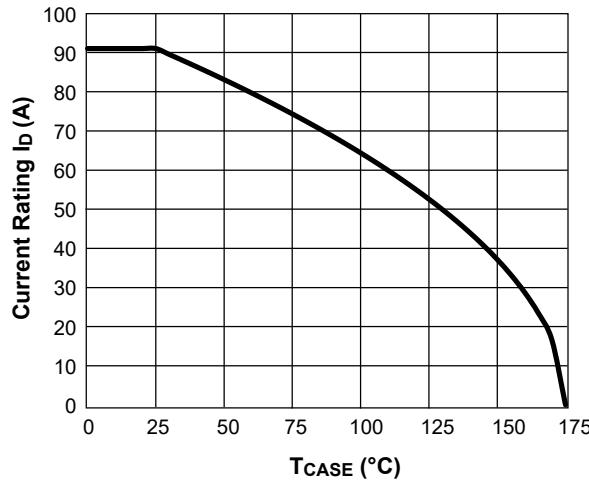


Figure 16. Current De-rating (Note 1)

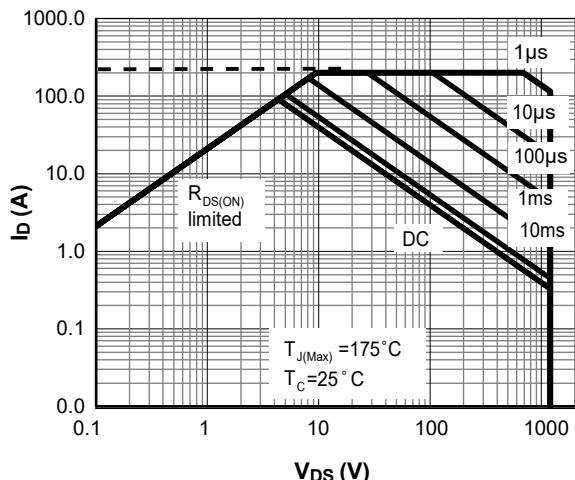


Figure 17. Maximum Forward Biased Safe Operating Area for AOGT020V120X2Q (Note 1)

Typical Electrical and Thermal Characteristics (Continued)

$T_A = 25^\circ\text{C}$, unless otherwise specified.

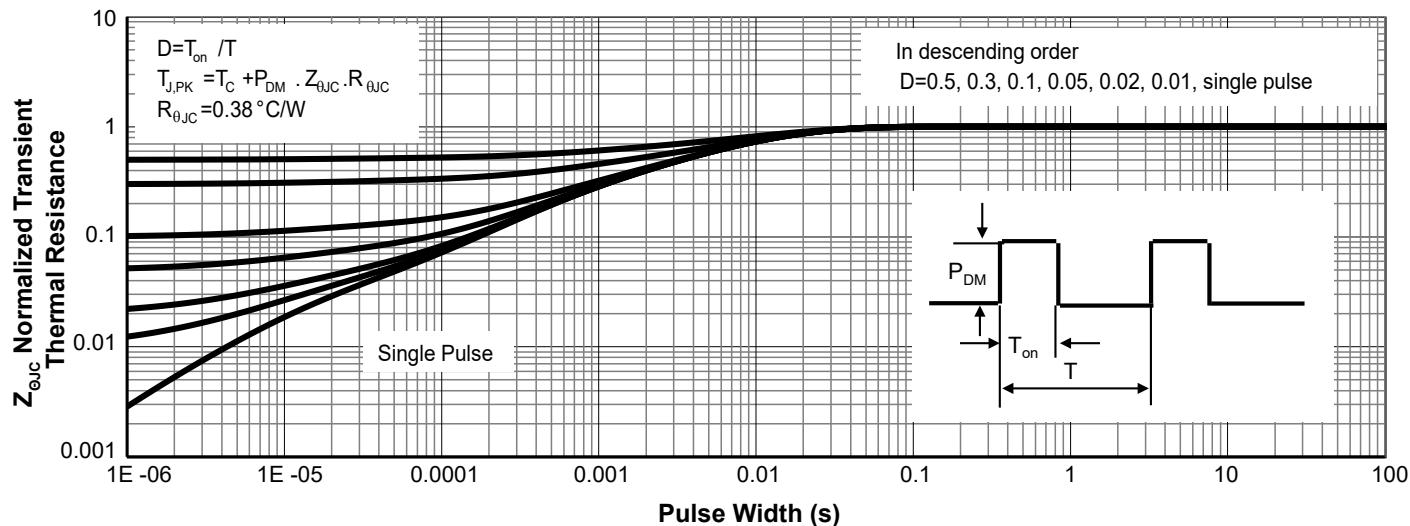


Figure 18. Normalized Maximum Transient Thermal Impedance for AOGT020V120X2Q (Note I)

Test Circuits and Waveforms

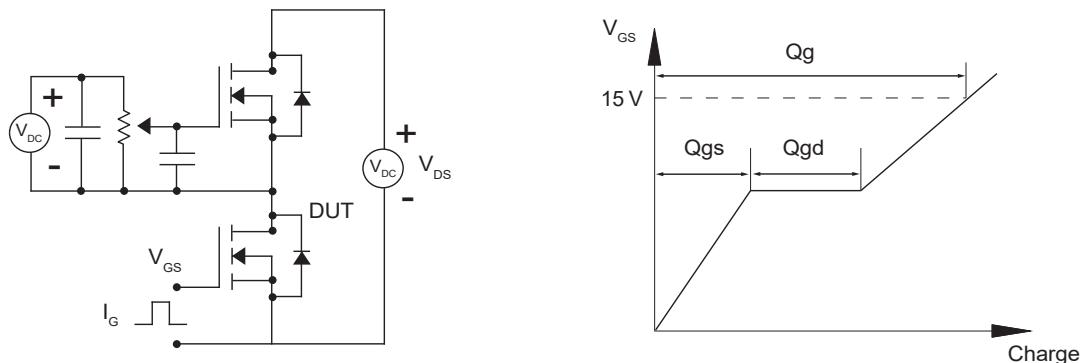


Figure 19. Gate Charge Test Circuits and Waveforms

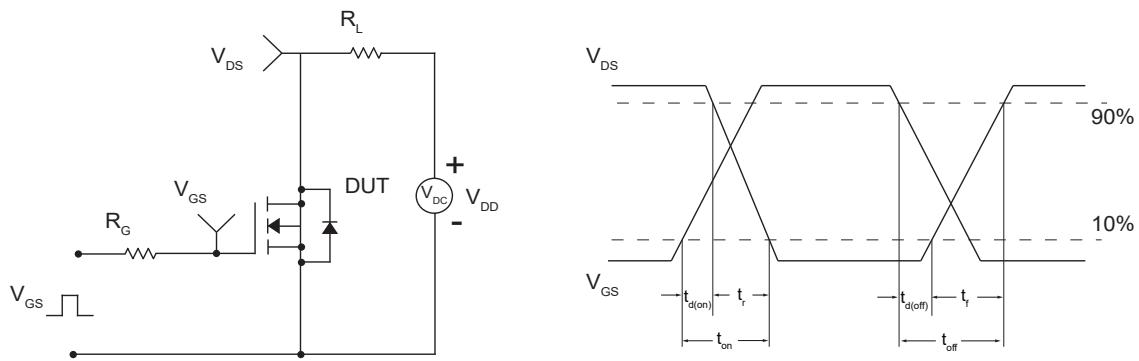


Figure 20. Resistive Switching Test Circuit and Waveforms

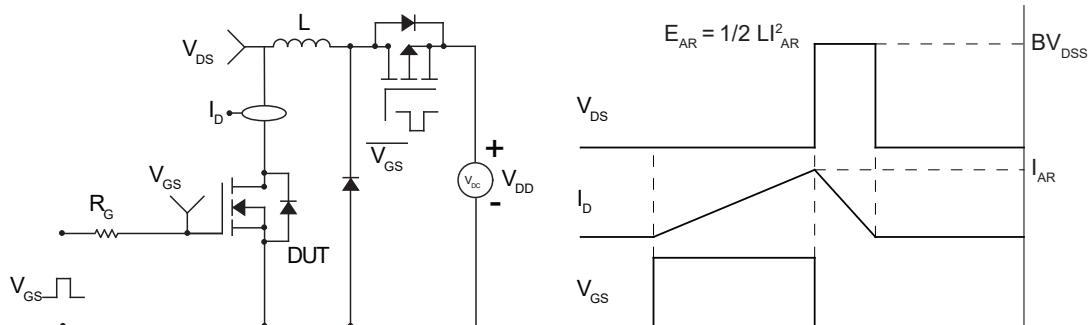


Figure 21. Unclamped Inductive Switching (UIS) Test Circuit and Waveforms

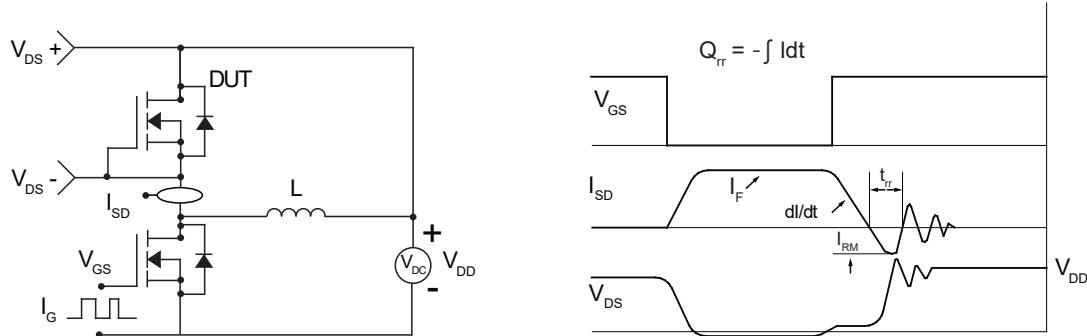
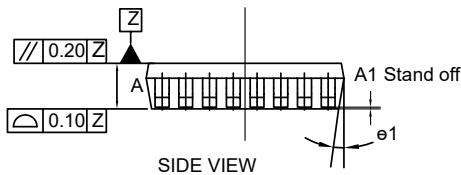
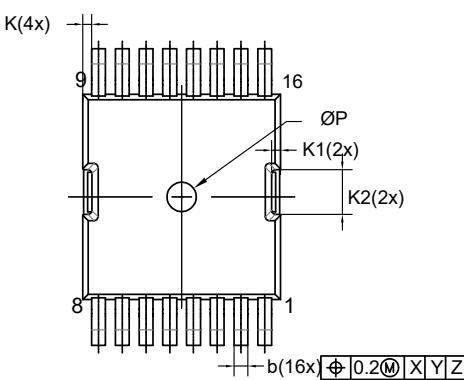
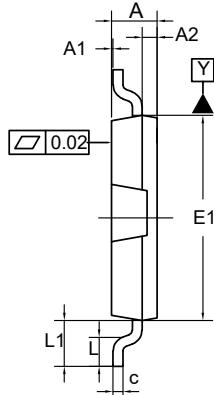
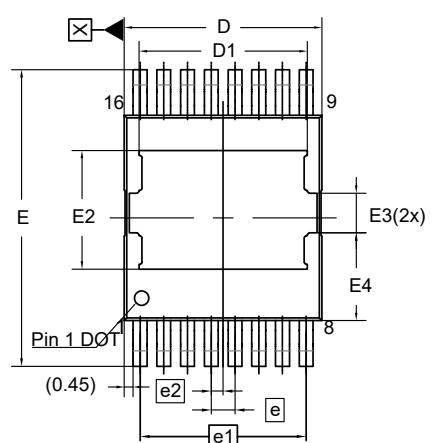
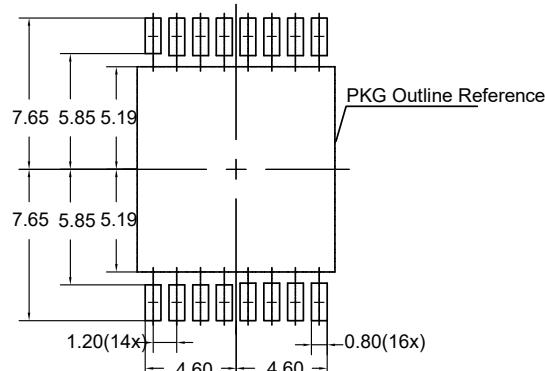


Figure 22. Diode Recovery Test Circuits and Waveforms

Package Dimensions, GTPAK-16L



LAND PATTERN RECOMMENDATIONS

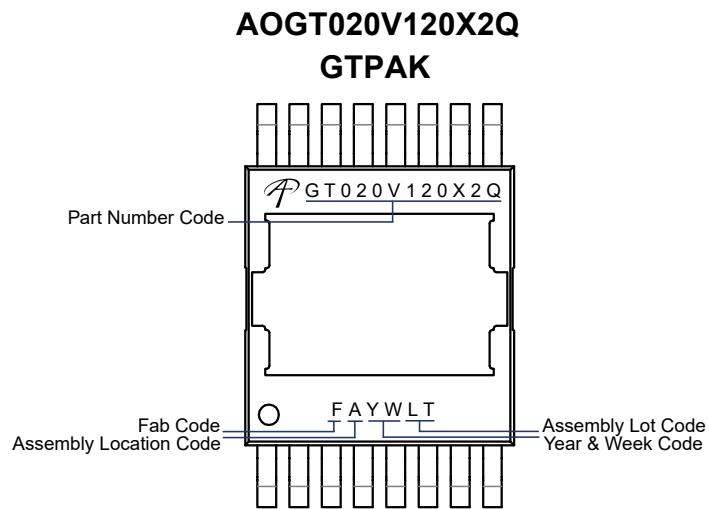


SYMBOLS	DIMENSION IN MILLIMETERS			DIMENSION IN INCHES		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	2.200	2.300	2.400	0.087	0.091	0.094
A1	0.010	0.075	0.145	0.000	0.003	0.006
A2	0.600	0.750	0.900	0.024	0.030	0.035
b	0.600	0.700	0.800	0.024	0.028	0.031
c	0.400	0.500	0.600	0.016	0.020	0.024
D	9.800	10.000	10.200	0.386	0.394	0.402
D1	8.300	8.500	8.700	0.327	0.335	0.343
E	14.800	15.000	15.200	0.583	0.591	0.598
E1	10.180	10.380	10.580	0.401	0.409	0.417
E2	5.805	6.005	6.205	0.229	0.236	0.244
E3	1.800	2.000	2.200	0.071	0.079	0.087
E4	4.240	4.440	4.640	0.167	0.175	0.183
e	1.200 BSC			0.047 BSC		
e1	8.400 BSC			0.331 BSC		
e2	0.600 BSC			0.024 BSC		
K	0.250	0.450	0.650	0.010	0.018	0.026
K1	0.260	0.460	0.660	0.010	0.018	0.026
K2	2.065	2.265	2.465	0.081	0.089	0.097
L	1.360	1.460	1.560	0.054	0.057	0.061
L1	2.210	2.310	2.410	0.087	0.091	0.095
P	1.300	1.500	1.700	0.051	0.059	0.067
θ1	10° TYP.			10° TYP.		

NOTES:

- A) PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
MOLD FLASH SHOULD BE LESS THAN 6 MIL.
- B) TOLERANCE 0.100 MILLIMETERS UNLESS OTHERWISE SPECIFIED.
- C) CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
- D) UNSPECIFIED DRAFT ANGLE FOR MOLD BODY IS 10deg
- E) () IS FOR REFERENCE

Part Marking



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2. A critical component in any component of a life support device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.